

Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 07977/279001/US5023/5025	Application No.
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)		Applicant Yamazaki, et al.			
(37 CFR §1.98(b))		Filing Date June 25, 2001		Group Art Unit	

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U.S. Patent Documents							
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
M>	AA	5,643,826	7/1/97	Ohtani, et al.			
M>	AB	5,923,962	7/13/99	Ohtani, et al.			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
M>	AL ✓	07-130652	5/19/95	Japan			Abstract only
M>	AM ✓	08-078329	3/22/96	Japan			Abstract only
	AN						
	AO						
	AP						

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
M>	AQ ✓	Ishihara, et al., "Microtexture Analysis of Location Controlled Large Si Grain Formed by Excimer-Laser Crystallization Method", AM-LCD 99, Digest of Technical Papers, pp. 99-102, July 1999, Tokyo, Japan.
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
<i>Matthew S.</i>	<i>2/12/2002</i>
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (Modified) DEC 26 2001 U.S. PATENT & TRADEMARK OFFICE	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-279001	Application No. 09/892,225
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Yamazaki, et al.	
		Filing Date June 25, 2001	Group Art Unit 2811

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
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	AD						
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**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
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	AL							
	AM							
	AN							
	AO							
	AP							

**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
MS	AQ ✓	U.S. Serial No. 09/874,204, filed June 6, 2001 entitled "Thin Film Transistors and Semiconductor Device", Specification 44 pages; 132 Claims; Abstract 1 page; Drawings 24 Figs.
↓	AR ✓	U.S. Serial No. 09/880,089, filed June 14, 2001 entitled "Semiconductor Device", Specification 65 pages; 50 Claims; Abstract 1 page; Drawings 45 Figs.
↓	AS ✓	U.S. Serial No. 09/882,265, filed June 18, 2001 entitled "Semiconductor Device", Specification 100 pages; 52 Claims; Abstract 1 page; Drawings 32 Figs.
	AT	

Examiner Signature <i>Matthew S. Son</i>	Date Considered <i>12/17/2001</i>
EXAMINER: Initials of citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	